



SEMINAR

Monday, 30.9.2019 at 13:00

Kolar's lecture hall

Correlative SEM/AFM/EDX microscopy – the impact of merging complementary microscopy techniques on nano-scale research and engineering

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ABSTRACT

The AFSEM™ platform, designed for enabling in-situ correlative experiments including SEM, FIB, EDX, AFM, MFM, C-AFM allows the user to overcome these limitations and cherry-pick the advantages:

- Fast finding of the ROI and Hi-Res lateral imaging (SEM),
- Fast real nano-scale 3d topography, mechanical and surface properties imaging (AFM), electrical and magnetic property imaging (C-AFM, MFM)
- Localised chemical (EDX) and crystallographic analysis (EBSD).

Kindly invited.